

Figure 3: Schematic shows the location of indents on the chip and on the workpiece

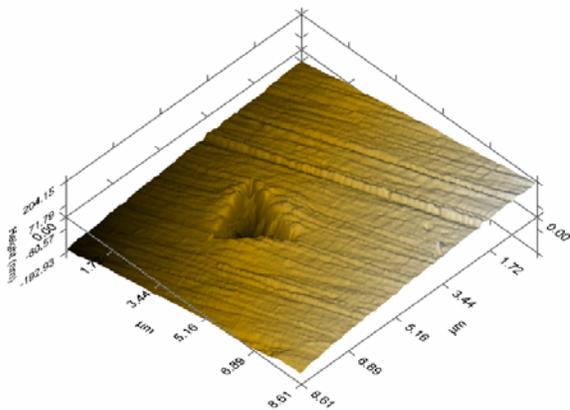


Figure 4: The SPM image of the Berkovich indent on the chip (10mN)

### Results

Figure 4 shows the SPM image of a typical indent on the chip. It can be seen that there is significant amount of pile-up. The hardness and the modulus of elasticity at the location of each indent were obtained by analyzing the unloading data of the load-displacement curves based on the standard Oliver and Pharr method [1]. About 10 to 15 outliers were ignored and the remaining data was used to find the average hardness and modulus in the chip and in the workpiece that are given in Table 1. Notice that there is

Table: 1

The results of constant load of 6 mN indentations in the chip and the workpiece

	Contact Depth (nm)		Modulus (GPa)		Hardness (GPa)	
	Mean	Stdv	Mean	Stdv	Mean	Stdv
Workpiece	231.21	16.59	203.55	11.02	4.47	0.59
Chip	212.16	18.63	186.23	17.89	5.29	0.84

degradation in modulus of the chip of about 10% as compared to that of the workpiece.

We tested the hypothesis that the mean value of the modulus of elasticity of the indents on the chip is smaller than the mean value of the modulus of elasticity of the indents on the workpiece. We could conclude that the modulus is degraded over the PSZ with essentially 100% confidence.

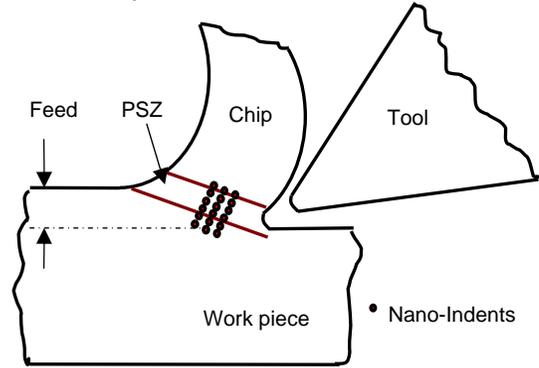


Figure 5: Performing nanoindents over the PSZ.

### Conclusion and Future work

Nanoindentation testing has been successfully used to measure the change in hardness and modulus of elasticity occurs in metal cutting.

Given that there is a degradation of the modulus from the workpiece to the chip, we are gearing up to carry out experiments to relate the degradation in modulus to the strain by performing numerous indents in the region of the PSZ as shown schematically in Figure 5. We are also working on techniques to compensate for pile-up. The experimental data will be used to obtain coefficients for models of ductile damage.

### References

- [1] W.C. Oliver and G.M. Pharr, J. Mater. Res., Vol 7, No. 6, June 1992
- [2] D. Krajcinovic and J. Lemaitre, "Continuum damage mechanics", CISM course, Springer-Verlag, 1987
- [3] C. Basaran et al, 55<sup>th</sup> Electronic Components and Technology Conference, ECTC, 2005